MICROWAVE POWER GaAs FET TIM5964-16UL

MICROWAVE SEMICONDUCTOR TECHNICAL DATA

FEATURES

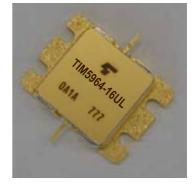
- ·BROAD BAND INTERNALLY MATCHED FET ·HIGH POWER
- P1dB= 42.5dBm at 5.9GHz to 6.4GHz

HIGH GAIN

G1dB= 10.0dB at 5.9GHz to 6.4GHz

- ·LOW INTERMODULATION DISTORTION
- IM3= -47dBc at Pout= 31.5dBm (Single Carrier Level)

·HERMETICALLY SEALED PACKAGE



CHARACTERISTICS	SYMBOL	CONDITIONS	UNIT	MIN.	TYP.	MAX.
Output Power at 1dB Gain Compression Point	P1dB	VDS= 10V IDSset= 3.6A f= 5.9 to 6.4GHz	dBm	41.5	42.5	
Power Gain at 1dB Gain Compression Point	G1dB		dB	9.0	10.0	_
Drain Current	IDS1		А		4.4	5.0
Gain Flatness	ΔG		dB			±0.6
Power Added Efficiency	ηadd		%		36	_
3rd Order Intermodulation Distortion	IM3	Two-Tone Test Po= 31.5dBm, ∆f= 5MHz (Single Carrier Level)	dBc	-44	-47	_
Drain Current	IDS2		А		4.4	5.0
Channel Temperature Rise	∆Tch	$(VDS \times IDS + Pin - P1dB) \\ \times Rth(c-c)$	°C			80

RF PERFORMANCE SPECIFICATIONS (Ta= 25°C)

Recommended Gate Resistance (Rg): 68 Ω

ELECTRICAL CHARACTERISTICS (Ta= 25°C)

CHARACTERISTICS	SYMBOL	CONDITIONS	UNIT	MIN.	TYP.	MAX.
Transconductance	gm	VDS= 3V IDS= 6.0A	S	_	3.6	_
Pinch-off Voltage	VGSoff	VDS= 3V IDS= 60mA	V	-1.0	-2.5	-4.0
Saturated Drain Current	IDSS	VDS= 3V VGS= 0V	А		10.5	_
Gate-Source Breakdown Voltage	VGSO	IGS= -200µA	V	-5	_	
Thermal Resistance	Rth(c-c)	Channel to Case	°C/W		1.5	1.8

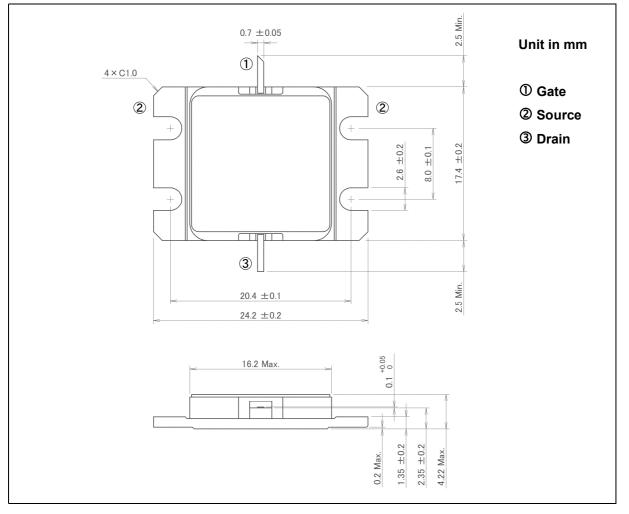
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ABSOLUTE MAXIMUM RATINGS (Ta= 25°C)

CHARACTERISTICS	SYMBOL	UNIT	RATING
Drain-Source Voltage	VDS	V	15
Gate-Source Voltage	VGS	V	-5
Drain Current	IDS	A	14.0
Total Power Dissipation (Tc= 25°C)	PT	W	83.3
Channel Temperature	Tch	°C	175
Storage Temperature	Tstg	°C	-65 to +175

PACKAGE OUTLINE (2-16G1B)



HANDLING PRECAUTIONS FOR PACKAGE MODEL

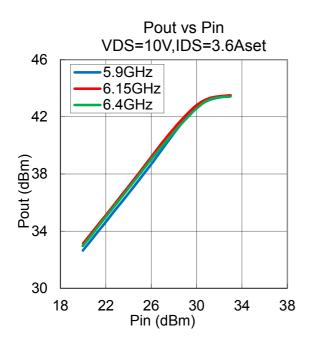
Soldering iron should be grounded and the operating time should not exceed 10 seconds at 260°C or 3 seconds at 350°C.

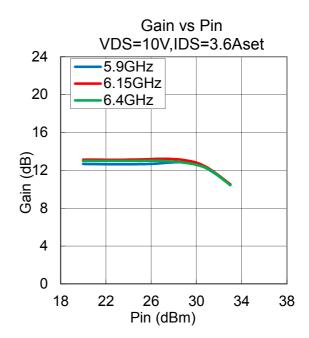
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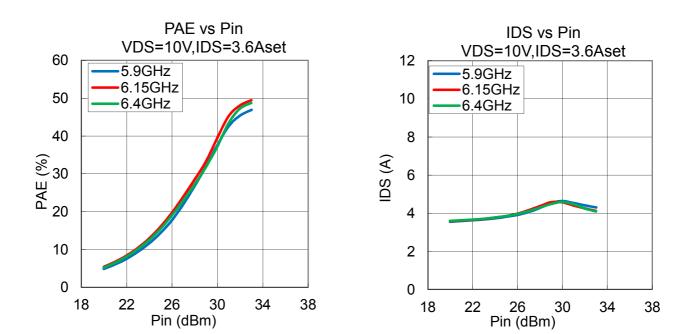
MICROWAVE SEMICONDUCTOR TECHNICAL DATA

·Pout, Gain, PAE, IDS vs. Pin

VDS= 10 V, IDSset= 3.6 A, f= 5.9, 6.15, 6.4 GHz, Ta= +25 °C







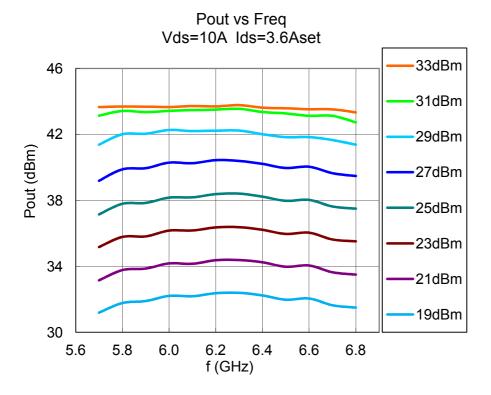
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MICROWAVE SEMICONDUCTOR TECHNICAL DATA

·Pout vs. Frequency

VDS= 10 V, IDSset= 3.6 A, Ta= +25 °C



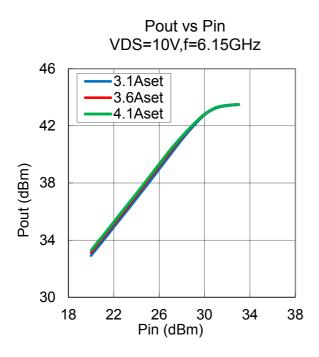
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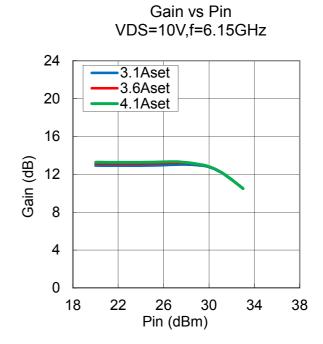
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MICROWAVE SEMICONDUCTOR TECHNICAL DATA

·Pout, Gain, PAE, IDS vs. Pin vs. IDSset

VDS= 10 V, IDSset= 3.1, 3.6, 4.1 A, f= 6.15 GHz, Ta= +25 °C





PAE vs Pin VDS=10V,f=6.15GHz

3.1Aset

3.6Aset

4.1Aset

60

50

40

20

10

0

18

22

26

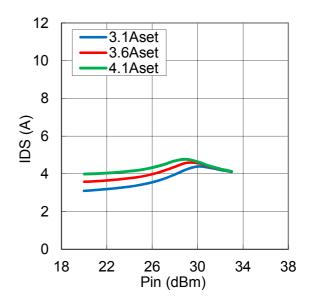
Pin (dBm)

30

34

PAE (%) 30

IDS vs Pin VDS=10V,f=6.15GHz



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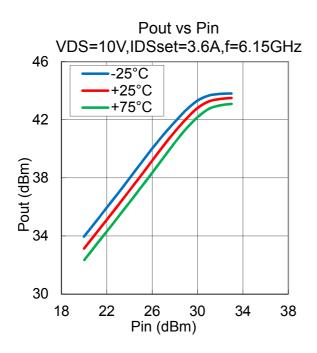
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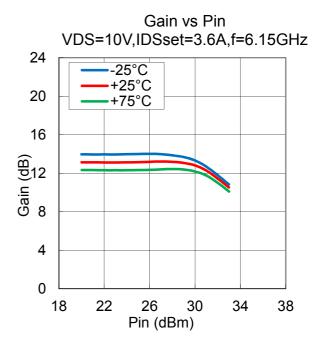
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MICROWAVE SEMICONDUCTOR TECHNICAL DATA

·Pout, Gain, PAE, IDS vs. Pin vs. Temperature

VDS= 10 V, IDSset= 3.6 A, f= 6.15 GHz, Ta= -25, +25, +75 °C





PAE vs Pin IDS vs Pin VDS=10V,IDSset=3.6A,f=6.15GHz VDS=10V,IDSset=3.6A,f=6.15GHz 60 12 -25°C -25°C +25°C +25°C 50 10 +75°C +75°C 40 8 (%)30 BAE 20 IDS (A) 6 4 10 2 0 0 22 22 18 26 30 34 38 18 26 30 34 38 Pin (dBm) Pin (dBm)

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